



Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 243203US2RD		SERIAL NO. 10/670,279	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Hideki SATAKE			
				FILING DATE September 26, 2003		GROUP 2814	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
LP ↓	AA	6,225,151	5/1/2001	GARDNER et al.		/	
	AB	5,827,774	10/27/1998	KITAJIMA			
	AC	6,300,664	10/9/2001	KUROI et al.			
	AD	6,288,433	9/11/2001	AKRAM et al.			
	AE	5,885,884	3/23/1999	JAN et al.			
	AF	6,242,356	6/5/2001	JANG et al.			
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
LP ↓	AO	EP 0 350 845	1/17/1990	EUROPE	X		
	AP	EP 0 706 204	4/10/1996	EUROPE	X		
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
LP LP	AW	YASUOKA, A. et al., "THE EFFECTS ON METAL OXIDE SEMICONDUCTOR FIELD EFFECT TRANSISTOR PROPERTIES OF NITROGEN IMPLANTATION INTO P+ POLYSILICON GATE", Japanese Journal of Applied Physics, Vol. 36, No. 2, February 1997, pgs. 617-622, XP-000735532					
	AX	HSING-HUANG TSENG, "FLUORINE DIFFUSION ON A POLYSILICON GRAIN BOUNDARY NETWORK IN RELATION TO BORON PENETRATION FROM P+ GATES", IEEE Electron Device Letters, Vol. 13, No. 1, January 1992, pgs. 14-16, XP 000244049					
	AY						
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner LONG PHAM				Date Considered 1/11/06			
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							